

SEMICONDUCTOR DEVICE AND METHOD FOR ALIGNING THE SEMICONDUCTOR DEVICE WITH PROBE CARD

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Abstract of JP10116866

PROBLEM TO BE SOLVED: To provide a semiconductor device that allows a probe to be aligned with pads with reliability even if the size of a chip is so large that the entire chip cannot be observed in the visual field of a microscope under proper magnification. **SOLUTION:** True pads 14, or electrodes with traces 15 connected therewith, and dummy pads 16, which are not electrodes with no traces 15 connected therewith, are formed. The pads are so set that the dummy pads 16 or the dummy pads 16 and the true pads 14 will be embraced in the visual field A under proper magnification when viewed through a microscope and the positional relation between the dummy pads 16 or the positional relation between the dummy pads 16 and the true pads 14 will differ from the positional relation between the true pads 14.

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